Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/826,207	LEE ET AL.
Examiner	Art Unit
Matthew D. Matzek	1771

	SEARCHED				
Class	Subclass	Date	Examiner		
442	130	10/7/07	мм		
	-				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
INVENTUL ; ASSIGNCE	10/7/05	µ ss		
EHT	10/7/05	мл		
102	10/7/07	MM		